Polarization: Measurement, Analysis, and Remote Sensing XI

David B. Chenault
Dennis H. Goldstein
Editors

5–6 May 2014
Baltimore, Maryland, United States

Sponsored and Published by
SPIE

Volume 9099

Proc. of SPIE Vol. 9099, 909901 · © 2014 SPIE · CCC code: 0277-786X/14/$18 · doi: 10.1117/12.2069547
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Please use the following format to cite material from this book:


ISSN: 0277-786X
ISBN: 9781628410365

Published by
SPIE
P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone +1 360 676 3290 (Pacific Time)· Fax +1 360 647 1445
SPIE.org

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